

Notice of References Cited		Application/Control No. 10/634,596	Applicant(s)/Patent Under Reexamination CHAN ET AL.	
		Examiner Margaret R Wambach	Art Unit 2816	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-4,446,567	05-1984	Iida et al.	377/79
X	B	US-4,890,308	12-1989	Imai, Masaharu	377/79
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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